


<b>Search Notes</b>  	<b>Application/Control No.</b>  10812075	<b>Applicant(s)/Patent Under Reexamination</b>  SEKIGUCHI ET AL.
	<b>Examiner</b>  Jaisle, Cecilia M	<b>Art Unit</b>  1624

SEARCHED			
Class	Subclass	Date	Examiner
514	235.8, 275	11/10/2009	C. Jaisle
544	310, 312, 122, 123	11/10/2009	C. Jaisle

SEARCH NOTES		
Search Notes	Date	Examiner
STN search and Inventor Names searched by STIC	6/24/2007	Cecilia Jaisle

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
514	235.8, 275	11/10/2009	C. Jaisle
544	301, 312, 122, 123	11/10/2009	C. Jaisle

/Cecilia M Jaisle/ Examiner.Art Unit 1624	
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